



Supporting Information

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Dual Passivation of Perovskite and SnO₂ for High-efficiency MAPbI₃ Perovskite Solar Cells

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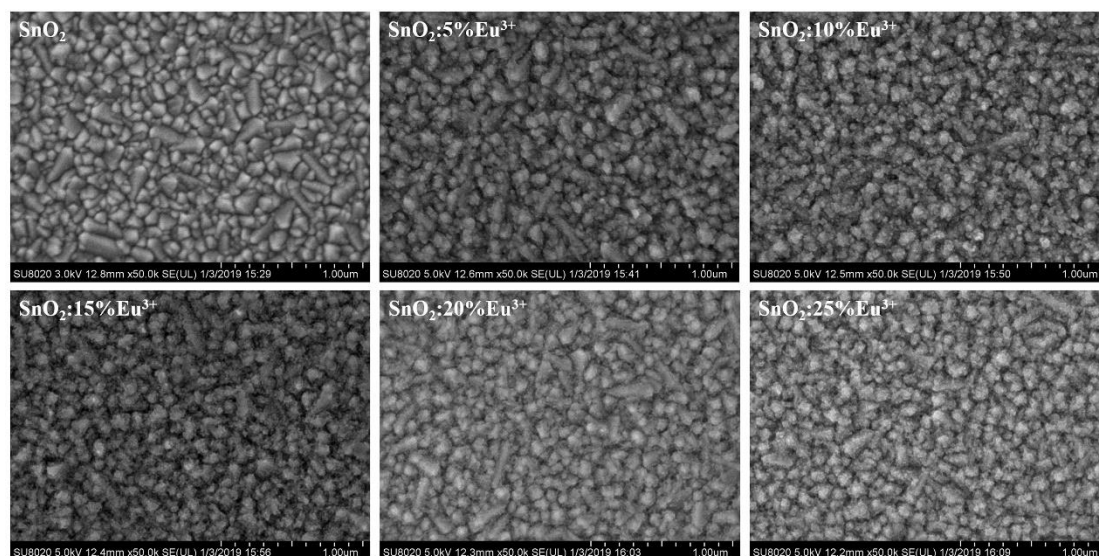


Fig. S1 The SEM images of SnO₂ and SnO₂:Eu³⁺ films.

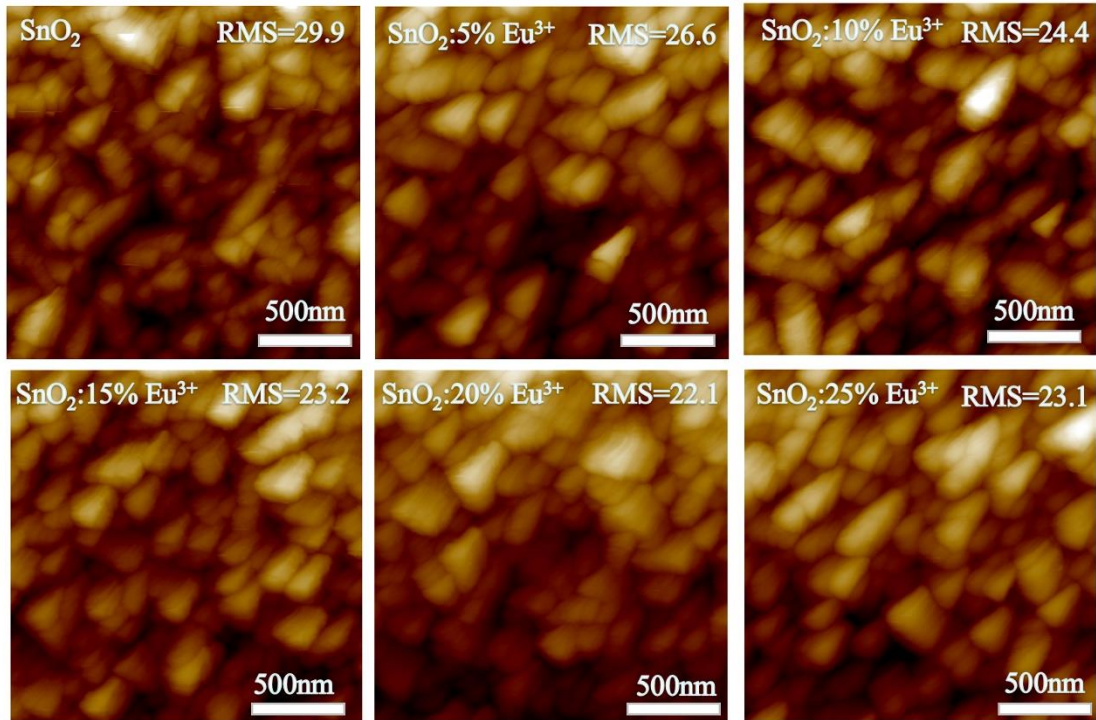


Fig. S2 Atomic force microscopy (AFM) images of SnO₂ and SnO₂:Eu³⁺ films deposited on FTO substrates

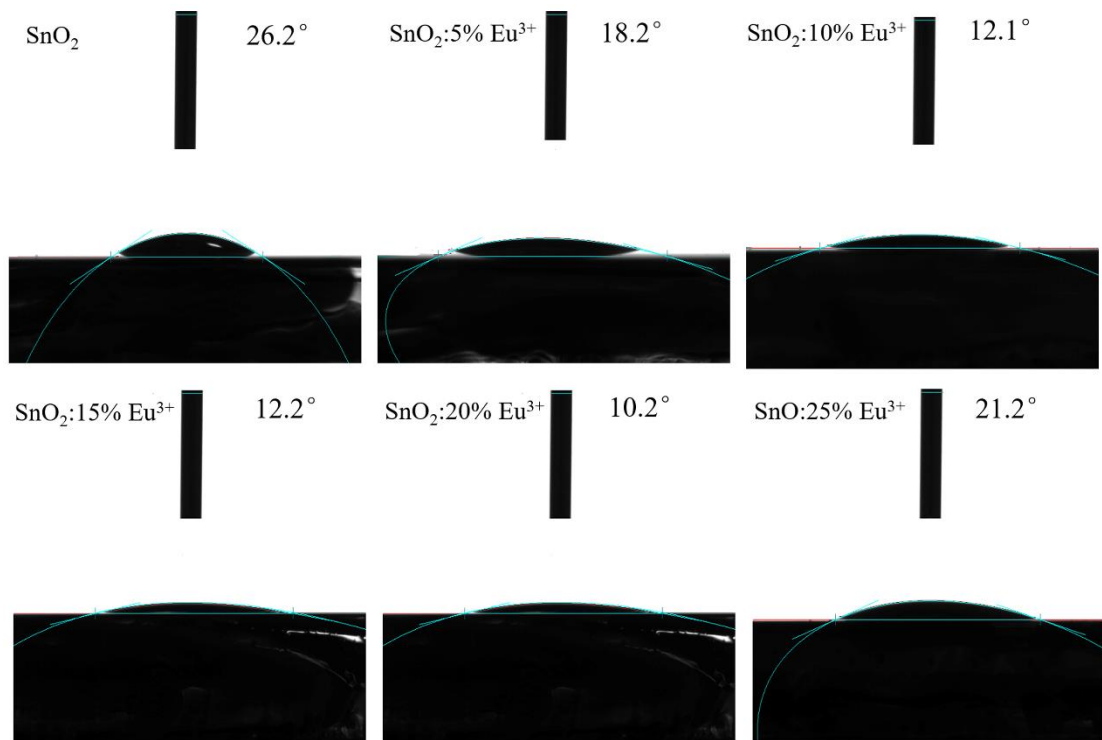


Fig. S3 The contact angles of SnO₂ and SnO₂:Eu³⁺ films.

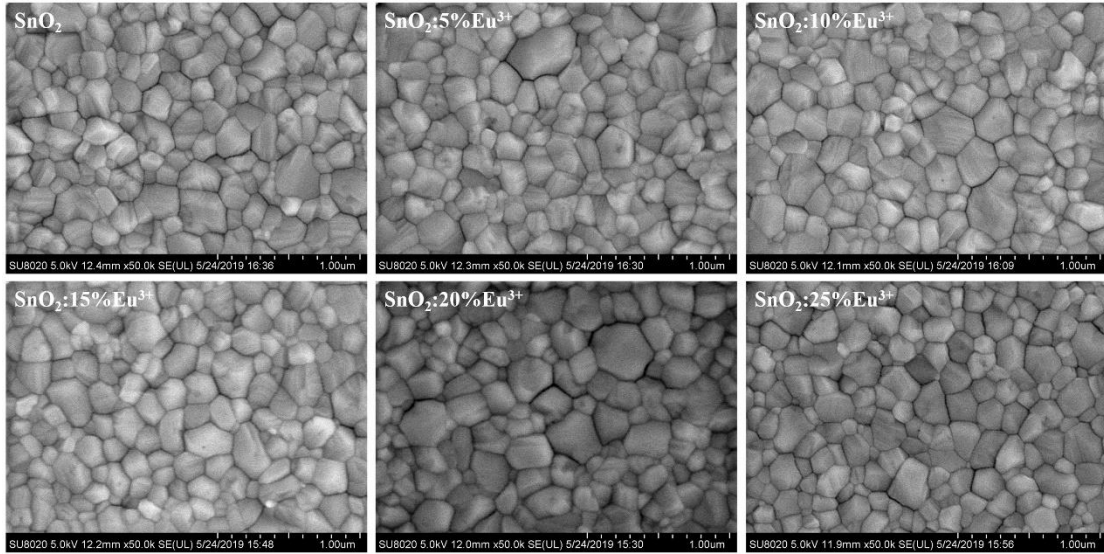


Fig. S4 The SEM images of perovskite films coated on SnO_2 and $\text{SnO}_2:\text{Eu}^{3+}$ films.

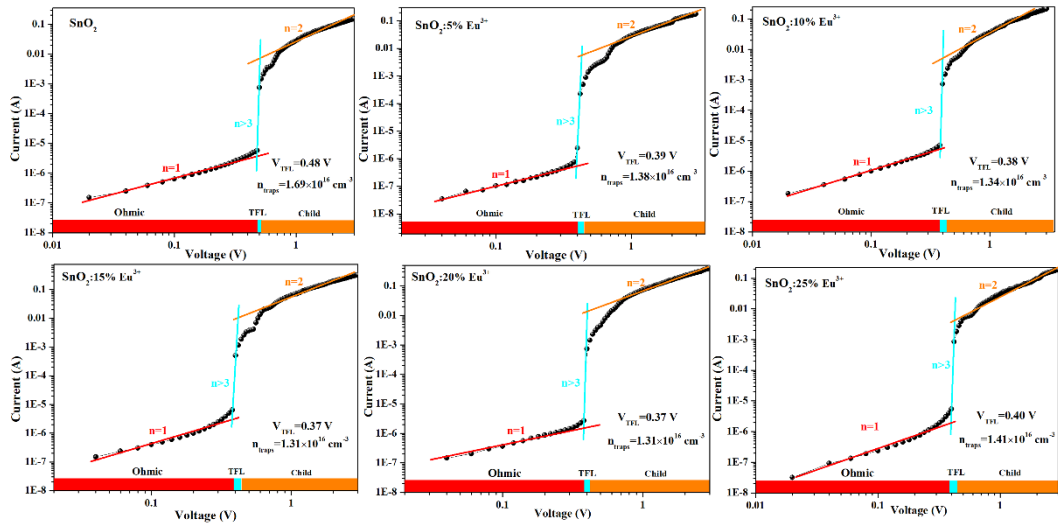


Fig. S5 Dark I - V curves of the electron-only devices with different ETL

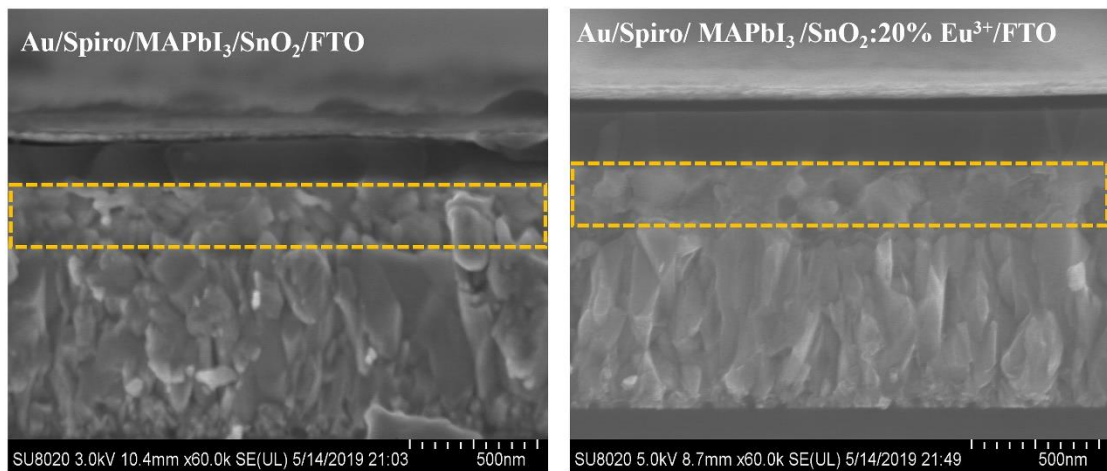


Fig. S6 The cross-sectional SEM images of PSCs with different ETL.

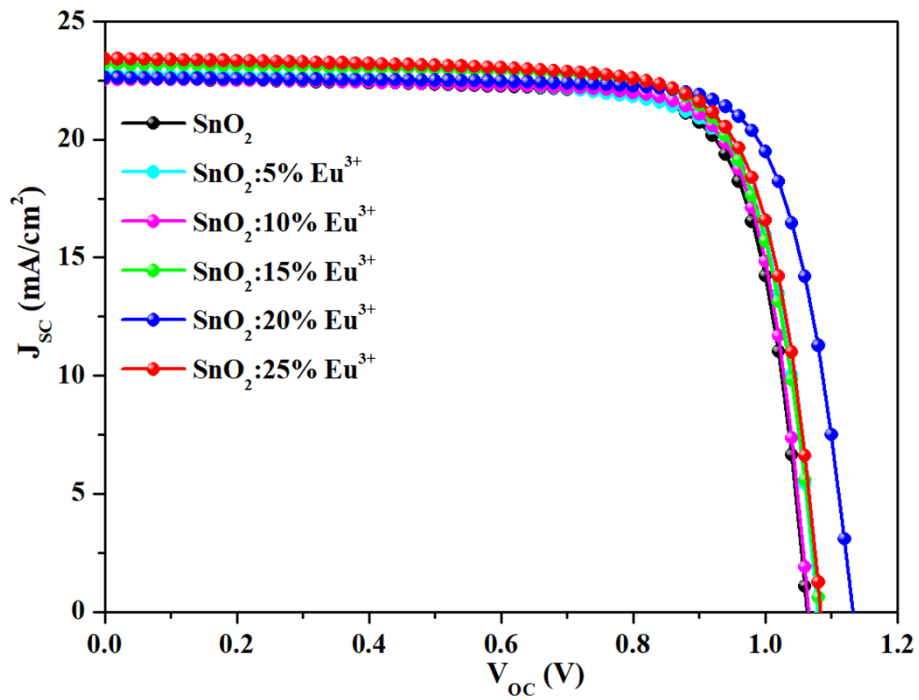


Fig.S7 J - V curves of the PSCs with different ETLs substrates.

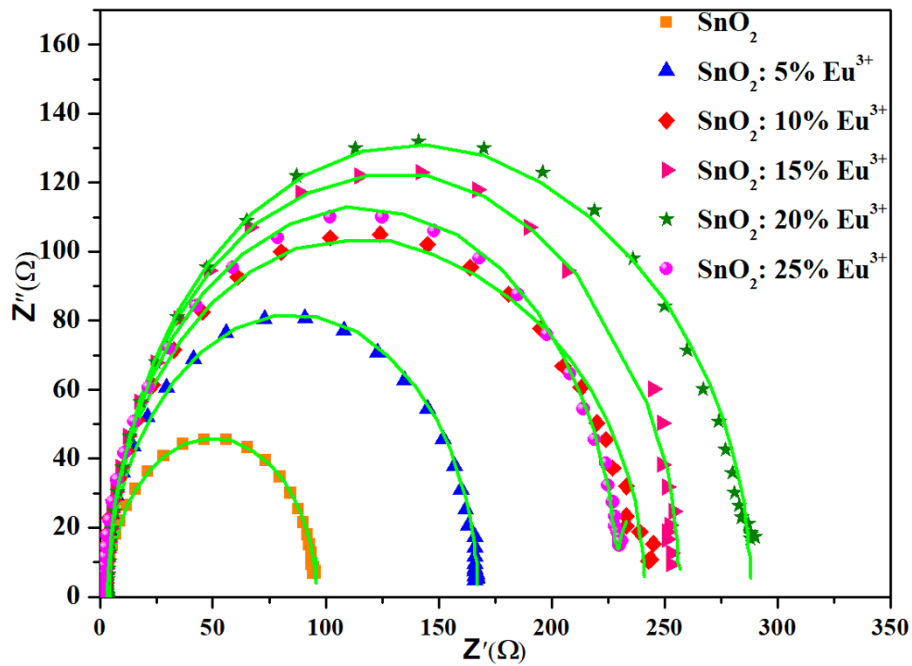


Fig.S8 EIS of planar-type PSCs with various ETLs.

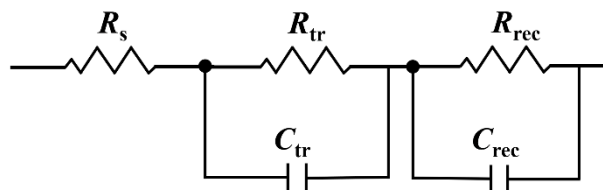


Fig.S9 Equivalent circuit in PSCs.

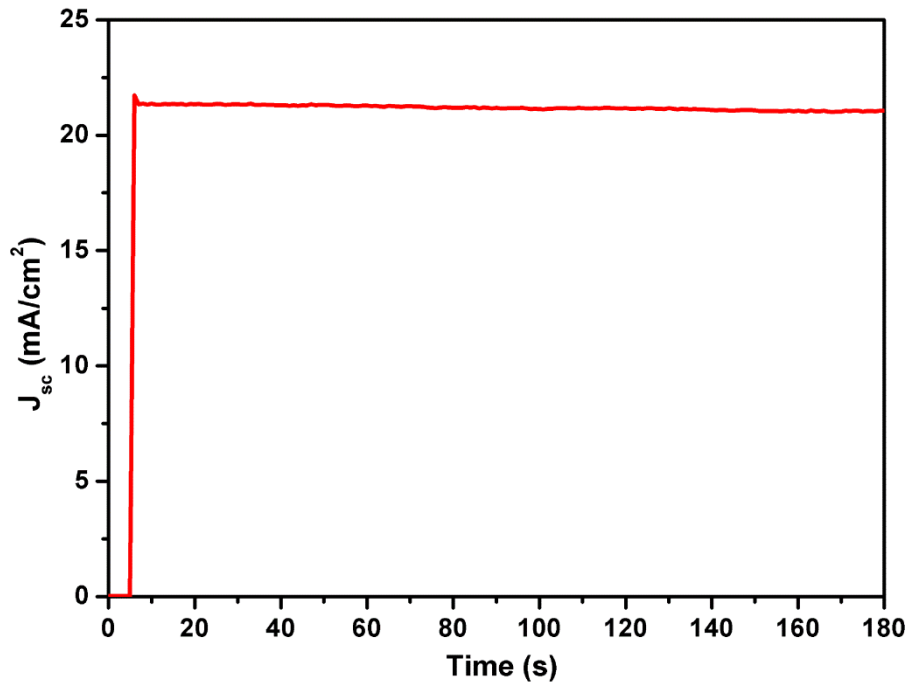


Fig.S10 Stable output curves of current densities of the device with $\text{SnO}_2:\text{Eu}^{3+}$ at the maximum power point.

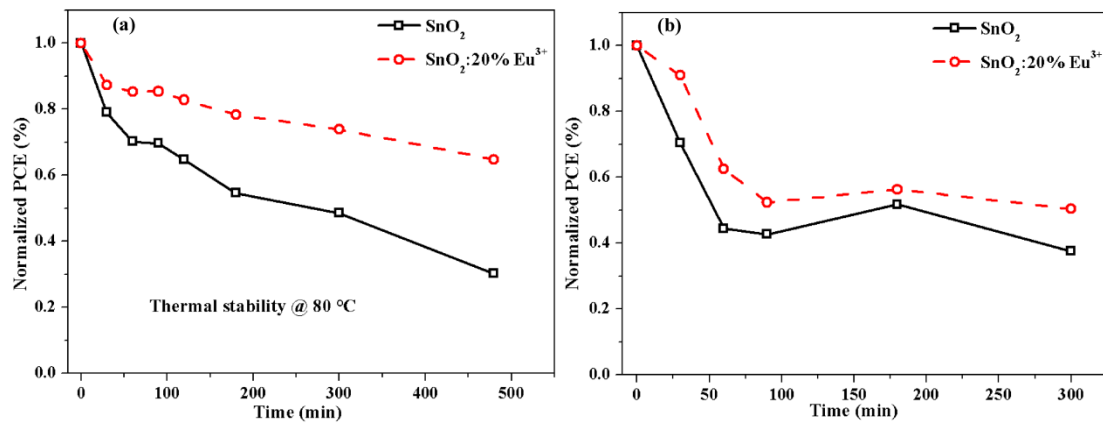


Fig.S11 Stability test for planar-type PSC devices with different ETLs without any encapsulation (a) at 80 °C in dry N_2 atmosphere; (b) under 100 mW cm^{-2} illumination and 40-50% humidity at 60 °C.

Supplementary Table 1 The average Hall coefficient, resistivity, mobility and carrier concentration of SnO_2 and $\text{SnO}_2:20\% \text{Eu}$ films.

| Sample | Average Hall coefficient ($\text{cm}^3 \text{C}^{-1}$) | Resistivity ($\Omega \cdot \text{cm}$) | Mobility ($\text{cm}^2 \text{V}^{-1} \text{s}^{-1}$) | Carrier concentration (cm^{-3}) |
|-------------------------------|--|--|--|--|
| SnO_2 | -2.59×10^5 | 6.24×10^2 | 4.14×10^2 | -2.41×10^{13} |
| $\text{SnO}_2:20\% \text{Eu}$ | -3.18×10^5 | 3.36×10^2 | 9.44×10^2 | -1.97×10^{13} |

Supplementary Table 2 Parameters of the TRPL spectra of perovskite films deposited on different substrates.

| Sample | τ_{ave} (ns) | τ_1 (ns) | % of τ_1 | τ_2 (ns) | % of τ_2 |
|---|----------------------|------------------|---------------|------------------|---------------|
| FTO/SnO ₂ /Perovskite | 35.20 | 4.38 | 39.5% | 37.55 | 60.5% |
| FTO/SnO ₂ :5% Eu/Perovskite | 17.45 | 3.94 | 33.08% | 18.85 | 66.9% |
| FTO/SnO ₂ :10% Eu/Perovskite | 6.07 | 2.93 | 43.59% | 7.07 | 56.41% |
| FTO/SnO ₂ :15% Eu/Perovskite | 6.16 | 2.76 | 38.71% | 7.01 | 61.29% |
| FTO/SnO ₂ :20% Eu/Perovskite | 4.54 | 7.65 | 13.05% | 3.53 | 86.95% |
| FTO/SnO ₂ :25% Eu/Perovskite | 9.85 | 3.04 | 36.32% | 10.93 | 63.68% |

Supplementary Table 3 Parameters of PSCs deposited on different substrates.

| The amount of Eu ³⁺ in SnO ₂ :Eu ³⁺ (mol%) | V_{oc} (V) | J_{sc} (mA cm ⁻²) | FF | PCE (%) |
|--|-----------------|------------------------------------|-------|---------|
| 0 | 1.06 | 22.57 | 77.77 | 18.66 |
| 5 | 1.07 | 22.75 | 76.73 | 18.84 |
| 10 | 1.10 | 22.41 | 76.77 | 19.08 |
| 15 | 1.10 | 22.25 | 78.76 | 19.28 |
| 20 | 1.13 | 22.61 | 78.76 | 20.14 |
| 25 | 1.08 | 23.41 | 76.68 | 19.46 |